Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/517,026	LECLAIR, PHILIPPE
Examiner Jason M. Perilla	**Art Unit** 2611	

SEARCHED

Class	Subclass	Date	Examiner
375	316	7/9/2007	JP
	295	7/9/2007	JP

SEARCH NOTES
(INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East USPAT/USPGPUB	7/9/2007	JP
Inventor Name Search	7/9/2007	JP
NPL Search IEEE Explore	7/9/2007	JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner